

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland



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Accreditation No.: **SCS 108**

Glossary

DAE data acquisition electronics
Connector angle information used in DAS Y system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters

- **DC Voltage Measurement:** Calibration Factor assessed for use in DAS Y system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- **Connector angle:** The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters as documented in the Appendix contain technical information as a result from the performance test and require no uncertainty.
 - **DC Voltage Measurement Linearity:** Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
 - **Common mode sensitivity:** Influence of a positive or negative common mode voltage on the differential measurement.
 - **Channel separation:** Influence of a voltage on the neighbor channels not subject to an input voltage.
 - **AD Converter Values with inputs shorted:** Values on the internal AD converter corresponding to zero input voltage
 - **Input Offset Measurement:** Output voltage and statistical results over a large number of zero voltage measurements.
 - **Input Offset Current:** Typical value for information; Maximum channel input offset current, not considering the input resistance.
 - **Input resistance:** Typical value for information: DAE input resistance at the connector, during internal auto-zeroing and during measurement.
 - **Low Battery Alarm Voltage:** Typical value for information. Below this voltage, a battery alarm signal is generated.
 - **Power consumption:** Typical value for information. Supply currents in various operating modes.



DC Voltage Measurement

A/D - Converter Resolution nominal

High Range: 1LSB = 6.1µV , full range = -100...+300 mV

Low Range: 1LSB = 61nV , full range = -1.....+3mV

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Calibration Factors	X	Y	Z
High Range	404.679 ± 0.1% (k=2)	403.480 ± 0.1% (k=2)	405.025 ± 0.1% (k=2)
Low Range	3.98633 ± 0.7% (k=2)	3.96375 ± 0.7% (k=2)	3.99940 ± 0.7% (k=2)

Connector Angle

Connector Angle to be used in DAS Y system	64.5 ° ± 1 °
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Appendix

1. DC Voltage Linearity

High Range	Reading (μV)	Difference (μV)	Error (%)
Channel X + Input	200004.4	1.89	0.00
Channel X + Input	20001.11	1.41	0.01
Channel X - Input	-19998.36	1.54	-0.01
Channel Y + Input	199996.1	3.42	0.00
Channel Y + Input	19999.75	0.35	0.00
Channel Y - Input	-19999.92	-0.12	0.00
Channel Z + Input	200002.7	1.29	0.00
Channel Z + Input	19996.85	-2.55	-0.01
Channel Z - Input	-20004.31	-4.61	0.02

Low Range	Reading (μV)	Difference (μV)	Error (%)
Channel X + Input	2000.0	0.09	0.00
Channel X + Input	200.02	0.02	0.01
Channel X - Input	-198.62	1.48	-0.74
Channel Y + Input	1999.6	-0.58	-0.03
Channel Y + Input	199.13	-0.57	-0.29
Channel Y - Input	-200.71	-0.61	0.31
Channel Z + Input	2000.1	-0.01	-0.00
Channel Z + Input	198.96	-1.14	-0.57
Channel Z - Input	-200.98	-0.98	0.49

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (μV)	Low Range Average Reading (μV)
Channel X	200	-5.28	-6.07
	- 200	6.79	6.12
Channel Y	200	-1.80	-1.60
	- 200	0.97	0.35
Channel Z	200	-9.76	-9.86
	- 200	7.56	7.61

3. Channel separation

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (μV)	Channel Y (μV)	Channel Z (μV)
Channel X	200	-	1.86	-0.66
Channel Y	200	2.28	-	2.89
Channel Z	200	1.68	-0.15	-



4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB)
Channel X	16056	16950
Channel Y	16153	13741
Channel Z	16441	16086

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Input 10MΩ

	Average (μV)	min. Offset (μV)	max. Offset (μV)	Std. Deviation (μV)
Channel X	0.32	-2.35	2.08	0.55
Channel Y	-1.83	-2.96	-0.72	0.47
Channel Z	-1.93	-3.00	-0.90	0.45

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance (Typical values for information)

	Zeroing (kOhm)	Measuring (MOhm)
Channel X	200	200
Channel Y	200	200
Channel Z	200	200

8. Low Battery Alarm Voltage (Typical values for information)

Typical values	Alarm Level (VDC)
Supply (+ Vcc)	+7.9
Supply (- Vcc)	-7.6

9. Power Consumption (Typical values for information)

Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA)
Supply (+ Vcc)	+0.01	+6	+14
Supply (- Vcc)	-0.01	-8	-9



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Accreditation No.: SCS 108

Client Sporton (Auden)

Certificate No: ET3-1787_May10

CALIBRATION CERTIFICATE

Object: ET3DV6 - SN:1787
Calibration procedure(s): QA CAL-01.v6, QA CAL-23.v3 and QA CAL-25.v2
Calibration date: May 18, 2010
This calibration certificate documents the traceability to national standards...
All calibrations have been conducted in the closed laboratory facility...
Calibration Equipment used (M&TE critical for calibration)
Primary Standards table with columns: Primary Standards, ID #, Cal Date (Certificate No.), Scheduled Calibration
Secondary Standards table with columns: Secondary Standards, ID #, Check Date (in house), Scheduled Check
Calibrated by: Jeton Kastrali, Laboratory Technician
Approved by: Katja Pokovic, Technical Manager
Issued: May 22, 2010

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Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C	modulation dependent linearization parameters
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- NORM(f)_{x,y,z}** = NORM_{x,y,z} * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DAS Y4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}; A, B, C** are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DAS Y4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DAS Y version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.



ET3DV6 SN:1787

May 18, 2010

Probe ET3DV6

SN:1787

Manufactured:	May 28, 2003
Last calibrated:	May 26, 2009
Recalibrated:	May 18, 2010

Calibrated for DASY/EASY Systems

(Note: non-compatible with DASY2 system!)



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May 18, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu\text{V}/(\text{V}/\text{m})^2$) ^A	1.60	1.79	2.10	$\pm 10.1\%$
DCP (mV) ^B	92.4	95.5	91.0	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300.0	$\pm 1.5\%$
			Y	0.00	0.00	1.00	300.0	
			Z	0.00	0.00	1.00	300.0	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying rectangular distribution and is expressed for the square of the field value.



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DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] [Ⓒ]	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
750	± 50 / ± 100	41.5 ± 5%	0.90 ± 5%	6.56	6.56	6.56	0.52	1.96 ± 11.0%
835	± 50 / ± 100	41.9 ± 5%	0.89 ± 5%	6.21	6.21	6.21	0.42	2.23 ± 11.0%
1750	± 50 / ± 100	40.1 ± 5%	1.37 ± 5%	5.36	5.36	5.36	0.49	1.18 ± 11.0%
1900	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	5.09	5.09	5.09	0.66	2.20 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	4.50	4.50	4.50	0.99	1.63 ± 11.0%

[Ⓒ] The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.



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DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
750	± 50 / ± 100	55.5 ± 5%	0.96 ± 5%	6.22	6.22	6.22	0.48	2.20 ± 11.0%
835	± 50 / ± 100	55.2 ± 5%	0.97 ± 5%	6.12	6.12	6.12	0.39	2.45 ± 11.0%
1750	± 50 / ± 100	53.4 ± 5%	1.49 ± 5%	4.72	4.72	4.72	0.63	2.90 ± 11.0%
1900	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	4.47	4.47	4.47	0.88	2.39 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	4.03	4.03	4.03	0.99	1.35 ± 11.0%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

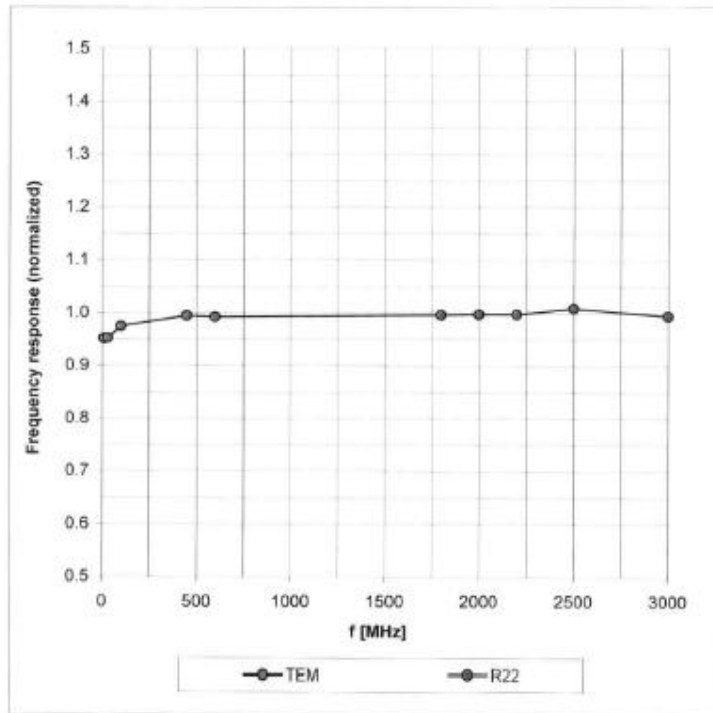


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Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



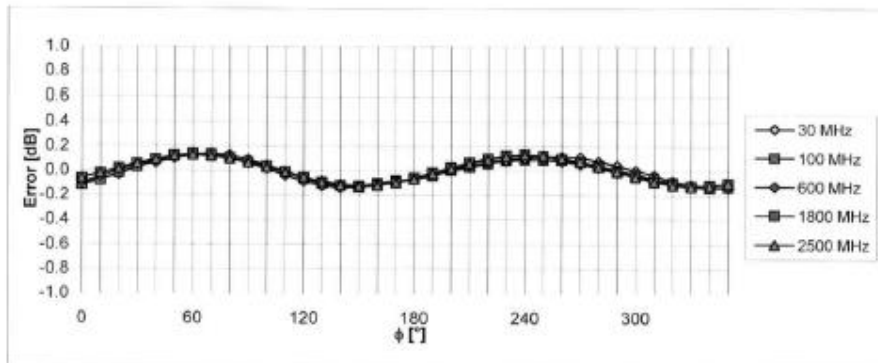
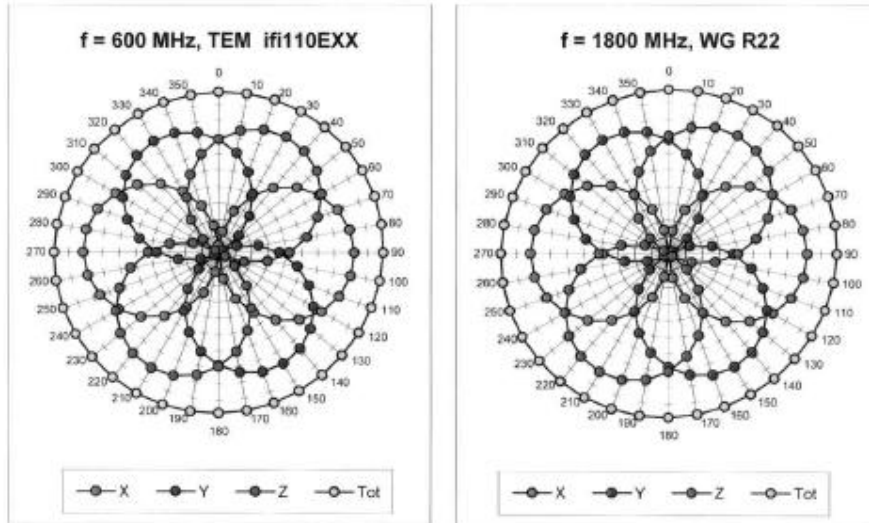
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ (k=2)



ET3DV6 SN:1787

May 18, 2010

Receiving Pattern (ϕ), $\vartheta = 0^\circ$



Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)